



LIST OF PUBLICATIONS
CITED BY APPLICANT

	<u>Atty. Docket No.</u> SEL 213	<u>Serial No.</u> 09/685,698
	<u>Applicant</u> Shunpei YAMAZAKI et al	
	<u>Filing Date</u> October 10, 2000	<u>Group</u> 2813

U. S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
<i>LL</i>	5,189,405	02/23/93	Yamashita et al	340	781	12/23/91
<i>LL</i>	5,920,080	07/06/99	Jones	257	40	05/08/98

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	APPLICANT	English Abstract	English Trans.	FILING DATE

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

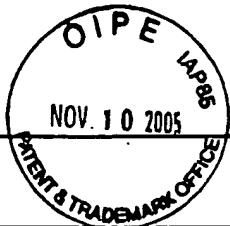
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EXAMINER: <i>hsema Schley</i>	DATE CONSIDERED: <i>5/19/06</i>
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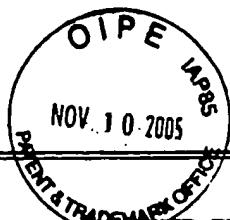


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US PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	3,484,793	12/16/69	Weigl	347	2	05/02/66
	3,878,517	04/15/75	Kasubuchi et al	346	75	06/01/73
	4,281,332	07/28/81	Horike	346	75	12/26/79
	4,788,629	11/29/88	Handy et al	362	23	10/29/86
	4,882,518	11/21/89	Cherry	313	512	05/25/88
	4,951,064	08/21/90	Kun et al	346	107	05/15/89
	4,994,540	02/19/91	Boerner et al	528	44	01/16/90
	4,999,229	03/12/91	Moritani et al	428	36.6	12/29/88
	5,059,148	10/22/91	McKenna et al	445	25	12/21/87
	5,278,223	01/11/94	Gruenewaelder et al	524	502	03/27/92
		5,304,419	Shores	428	355	03/09/92
		5,334,539	Shinar et al	437	1	01/29/93
		5,643,826	Ohtani et al	437	88	10/25/94
		5,663,573	Epstein et al	257	40	03/17/95
		5,684,365	Tang et al	315	169.3	12/14/94
		5,747,930	Utsugi	313	504	05/17/95
		5,770,892	Chan et al	257	903	06/02/95
		5,821,003	Uemura et al	428	690	09/20/96
		5,839,456	Han	134	104.1	08/20/97
		5,882,761	Kawami et al	428	69	11/19/96
		5,923,962	Ohtani et al	438	150	04/28/95
		5,928,794	Kalinowski et al	428	447	12/03/97
		5,962,962	Fujita et al	313	412	03/05/97
		5,972,419	Roitman	427	66	06/13/97
		6,057,647	Kurosawa et al	315	169.3	12/22/98
		6,087,771	Roitman	313	503	08/31/99
		US 2001/ 0001050 A1	Miyashita et al	428	690	12/08/00
		6,251,712 B1	Tanaka et al	438	143	09/12/97
		US 2002/ 0075422 A1	Kimura et al	349	43	07/10/01
		6,440,877 B1	Yamazaki et al	438	780	06/27/00
	US 2002/ 0197394 A1	Yamazaki et al	427	66	08/16/02	
	6,531,713 B1	Yamazaki	257	59	03/17/00	



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	DOCUMENT NUMBER	DATE	NAME	English Abstract	English Trans.	FILING DATE
	JP 62-090260	04/24/87	TDK Corp.	X		10/16/85
	EP 0 347 058	12/20/89	Nordson Corp.	X		05/26/89
	JP 07-130652	05/19/95	Semiconductor Energy Lab Co Ltd.	X		10/29/93
	JP 08-078159	03/22/96	Idemitsu Kosan Co.	X		09/08/94
	EP 0 717 446	06/19/96	Eastman Kodak Co.	X		12/05/95
	JP 08-234683	09/13/96	Eastman Kodak Co.	X		12/12/95
	JP 08-330602	12/13/96	Semiconductor Energy Lab Co Ltd.	X		03/27/96
	EP 0 776 147	05/28/97	Pioneer Electronic Corp.	X		11/20/96
	JP 09-148066	06/06/97	Pioneer Electronic Corp.	X		11/24/95
	EP 0 781 075	06/25/97	Idemitsu Kosan Co.	X		09/05/95
	JP 09-194831	07/29/97	NEC Corp.	X		01/25/96
	JP 10-189525	07/21/98	LG Semicon Co Ltd.	X		12/24/97
	EP 0 862 156	09/02/98	Seiko Epson Corp.	X		09/18/97
	JP 10-270363	10/09/98	Semiconductor Energy Lab Co Ltd.	X		03/27/97
	EP 0 883 191	12/09/98	Canon Kabushiki Kaisha	X		05/29/98
	JP 11-016679	01/22/99	Hewlett Packard Co	X		06/08/98
	JP 11-054272	02/26/99	Seiko Epson Corp.	X		07/31/97
	WO 99/10861	03/04/99	Seiko Epson Corp.	X		08/18/98
	EP 0 903 778	03/24/99	Stella Chemifa Kabushiki Kaisha	X		12/15/97
	A1		Seiko Epson Corp.	X		08/18/98
	EP 0 940 796	09/08/99	Semiconductor Energy Lab Co Ltd.	X		03/15/00
	JP 2000-340798	12/08/00	Semiconductor Energy Lab Co Ltd.	X		10/12/00
	EP 1 093 166	04/18/01	Energy Lab Co Ltd.			

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- 1) WU, C.C. et al, "Integration of Organic LED's and Amorphous Si TFT's Onto Unbreakable Metal Foil Substrates," International Electron Devices Meeting, San Francisco, CA, December 8-11, 1996, IDEM 1996 Technical Digest, pp. 957-959, (1996).
- 2) SHIM, H. et al, "Electrical and Optical Polymer Systems," Donald L. Wise, ed., p. 938, (1998).
- 3) HART, J.A. et al, "A History of Electroluminescent Displays," <http://www.indiana.edu/hightech/fpd/papers/ELDs.html> pp. 1-18 (1999).
- 4) European Search Report re application no. EP 00122446.8, dated June 26, 2001.
- 5) EPO Office Action re application no. EP 00122446.8, dated November 4, 2003.
- 6) European Search Report re application no. EP 00113577.1, dated March 1, 2004.
- 7) European search report re application no. EP 01102402.3, dated April 25, 2005.

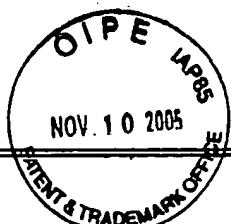
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<i>SL</i>	5,757,396	05/26/98	Bruner	347	27	06/30/94
	US 2001/0023661 A1	09/27/01	Hiroki et al	118	300	02/02/01
<i>SL</i>	US 2003/0003231 A1	01/02/03	Kiguchi et al	427	282	01/19/99
	US 2003/0196597 A1	10/23/03	Yamazaki et al	118	300	04/22/03
<i>SL</i>	US 2004/0048001 A1	03/11/04	Kiguchi et al	427	421	05/27/03
	6,797,980 B2	09/28/04	Takiguchi et al	257	40	11/29/01
<i>SL</i>	6,830,494 B1	12/14/04	Yamazaki et al	445	24	10/06/00
	US 2005/0012445 A1	01/20/05	Yamazaki et al	315	500	07/30/04
<i>SL</i>	US 2005/0035708 A1	02/17/05	Yamazaki et al	313	505	07/08/04

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<i>SL</i>	JP 08-085203	04/02/96	Nikon Corp.	X		09/14/94
<i>SL</i>	JP 10-060331	03/03/98	Kao Corp.	X		08/13/96
<i>SL</i>	EP 0 930 641	07/21/99	Seiko Epson Corp.			01/19/98
<i>SL</i>	JP 11-268296	10/05/99	Toshiba Corp.	X		03/26/98
	DE 19918193	11/25/99	Cambridge Display Technology Ltd.	X		04/22/90

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EXAMINER:	<i>hanna Schulte</i>	DATE CONSIDERED:	<i>7/22/06</i>
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<i>J</i>	6,585,910 B1	07/01/03	Kikuyama et al	252	79.3	03/36/99
<i>SL</i>	6,776,844 B2	08/17/04	Yonekura et al	118	621	03/26/02

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